

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Low-voltage switchgear and controlgear –
Part 2: Circuit-breakers**

**Appareillage à basse tension –
Partie 2: Disjoncteurs**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

LOW-VOLTAGE SWITCHGEAR AND CONTROLGEAR –

Part 2: Circuit-breakers

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The main changes introduced in this new edition are an amendment to the verification of dielectric properties, the improvement of EMC clauses in Annexes B, F, J and M, and the addition of a new Annex O regarding instantaneous trip circuit-breakers.

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The technical content is therefore identical to the base edition and its amendment and has been prepared for user convenience.

It bears the edition number 4.1.